ket No.: 006217 USA/Consilium/Consilium

PATENT/OFFICIAL CS

#### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

e Application of

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Nicholas A. WARD et al.

APR 0 1 2004

Serial No. 09/927,444

Group Art Unit: 2125

**Technology Center 2100** 

Filed: August 13, 2001

Examiner: Sean P. Shechtman

For:

DYNAMIC CONTROL OF WAFER PROCESSING PATHS IN SEMICONDUCTOR

MANUFACTURING PROCESSES

## SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner for Patents Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This submission does not constitute a representation that a search has been made or that no better art exists and does not constitute an admission or representation that any of the listed documents is material or constitutes prior art. If it should be determined that any of the listed documents does not constitute prior art under the United States law, Applicants reserve the right

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## Serial No. 09/927,444

to present to the Office the relevant facts and law regarding the appropriate status of such document.

Please charge the fee of \$180.00 under 37 CFR 1.17(p) to Deposit Account No. 08-0219. The Commissioner is hereby authorized to charge any additional fees that may be required for this submission, or credit any overpayment to deposit account no. 08-0219.

Respectfully submitted,

HALE AND DORR LLP

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Date: 3/29/04

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INFORMATION DISCLOSURE				ATTY. DOCKET NO. 006217 USA/Consilium/Consilium		SERIAL NO. 09/927,444		
CITATION IN AN								
APPLICATION								
IPE								
(PTO-1449)								
				APPLICANT Nicholas A. WARD et al.				
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U.S. PATENT DO						2123		
EXAMINER'S		1	J.S. PATENT DU	CUMENTS		<u> </u>	FILING	
INITIALS	PATENT NO.	DATE	NAME		CLASS	SUBCLASS	DATE	
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EXAMINER	EXAMINER DATE CONSIDERED							

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

# SHEET 2 OF 2

### ATTY, DOCKET NO. SERIAL NO. 09/927,444 006217 INFORMATION DISCLOSURE USA/Consilium/Consilium CITATION IN AN APPLICATION (PTO-1449) APPLICANT Nicholas A. WARD et al. FILING DATE GROUP August 13, 2001 2125 FOREIGN PATENT DOCUMENTS Translation **EXAMINER'S** PATENT NO. DATE COUNTRY CLASS SUBCLASS INITIALS Yes X 0 397 924 A1 11/22/90 Europe OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.) Rocha, Joao and Carlos Ramos. September 12, 1994. "Task Planning for Flexible and Agile Manufacturing Systems." Intelligent Robots and Systems '94. Advanced Robotic Systems and the Real World, IROS '94. Proceedings of the IEEE/RSJ/GI International Conference on Munich, Germany 12-16 Sept. 1994. New York, New York: IEEE. pp. 105-112. March 15, 2002. Office Action for U.S. Serial No. 09/469,227, filed December 22, 1999. March 29, 2002. Office Action for U.S. Serial No. 09/363,966, filed July 29, 1999. June 20, 2002. Office Action for U.S. Serial No. 09/619,044, filed July 19, 2000. September 26, 2002. Office Action for U.S. Serial No. 09/637,620, filed August 11, 2000. October 23, 2002. Office Action for U.S. Serial No. 09/469,227, filed December 22, 1999 December 17, 2002. Office Action for U.S. Serial No. 09/363,966, filed July 29, 1999 February 10, 2003. Office Action for U.S. Serial No. 09/619,044, filed July 19, 2000. APR 0 1 2004 April 9, 2003. Office Action for U.S. Serial No. 09/928,474, filed August 14, 2001. May 8, 2003. Office Action for U.S. Serial No. 09/637,620, filed August 11, 2000. Technology Center 2 00 June 18, 2003. Office Action for U.S. Serial No. 09/655,542, filed September 6, 2000. August 8, 2003. International Search Report for PCT/US03/08513. August 25, 2003. Office Action for U.S. Serial No. 10/100,184, filed March 19, 2002. September 15, 2003. Office Action for U.S. Serial No. 09/928,474, filed August 14, 2001. November 5, 2003. Office Action for U.S. Serial No. 10/172,977, filed June 18, 2002. December 1, 2003. Office Action for U.S. Serial No. 10/173,108, filed June 18, 2002. December 11, 2003. Office Action for U.S. Serial No. 09/943,383, filed August 31, 2001. December 16, 2003. International Search Report for PCT/US03/23964. January 23, 2004. International Search Report for PCT/US02/24860. February 2, 2004. Office Action for U.S. Serial No. 09/363,966, filed July 29, 1999. DATE CONSIDERED **EXAMINER**

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